

<b>Notice of References Cited</b>	Application/Control No. 10/795,817		Applicant(s)/Patent Under Reexamination VENKATESH ET AL	
	Examiner Sam K. Ahn		Art Unit 2611	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2003/0012270	01-2003	Zhou et al.	375/150
*	B	US-2004/0170238	09-2004	Matsuyama et al.	375/343
*	C	US-2004/0240486	12-2004	Venkatesh et al.	370/537
*	D	US-2006/0133456	06-2006	Ettorre et al.	375/148
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	J	US-			
	K	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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